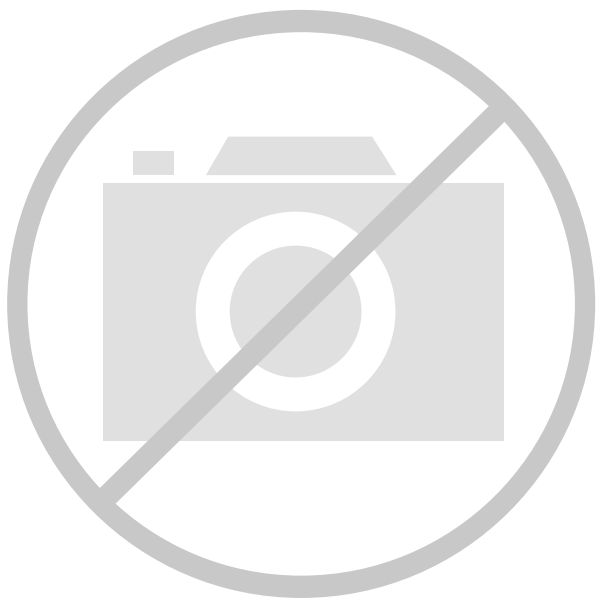




Welcome to [E-XFL.COM](https://www.e-xfl.com)

Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

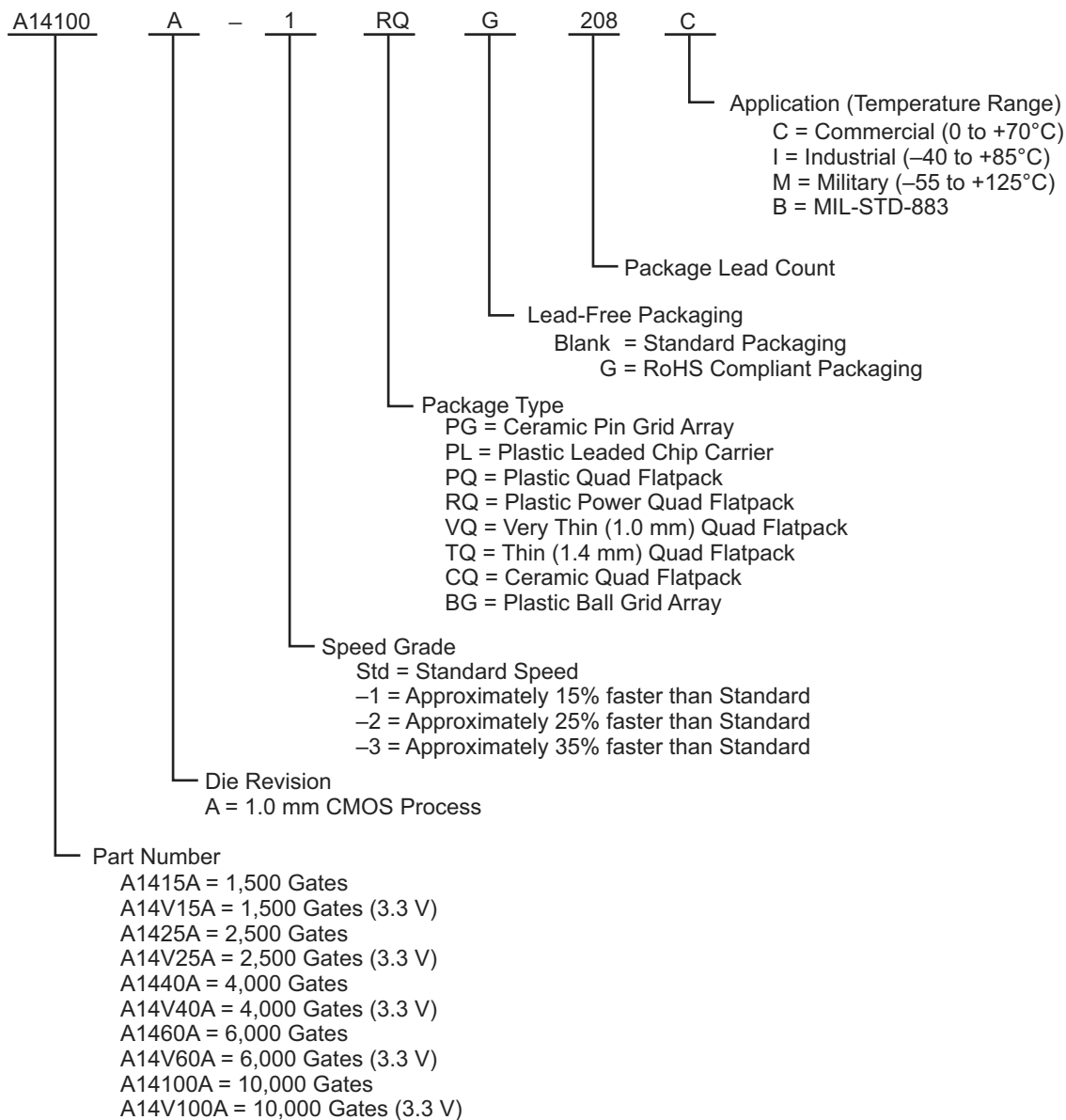
Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Obsolete
Number of LABs/CLBs	848
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	168
Number of Gates	6000
Voltage - Supply	4.5V ~ 5.5V
Mounting Type	Through Hole
Operating Temperature	0°C ~ 70°C (TA)
Package / Case	207-BCPGA
Supplier Device Package	207-CPGA (44.96x44.96)
Purchase URL	https://www.e-xfl.com/product-detail/microsemi/a1460a-pg207c

Ordering Information



Notes:

1. The -2 and -3 speed grades have been discontinued.
2. The Ceramic Pin Grid Array packages PG100, PG133, and PG175 have been discontinued in all device densities, speed grades, and temperature grades.
3. The Plastic Ball Grid Array package BG225 has been discontinued in all device densities (specifically for A1460A), all speed grades, and all temperature grades.
4. Military Grade devices are no longer available for the A1440A device.
5. For more information about discontinued devices, refer to the Product Discontinuation Notices (PDNs) listed below, available on the Microsemi SoC Products Group website:
PDN March 2001
PDN 0104
PDN 0203
PDN 0604
PDN 1004

ACT 3 Family Overview

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Datasheet Information

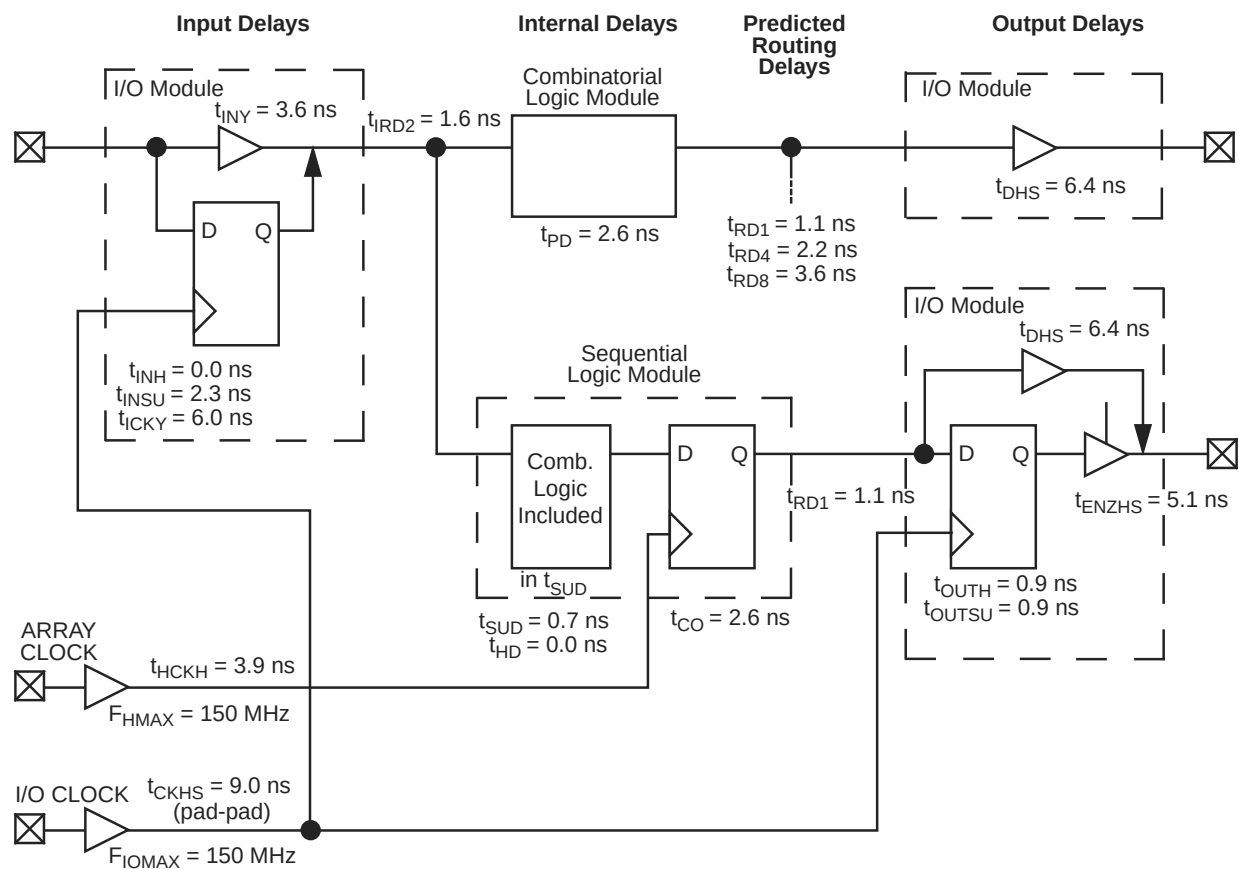
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Table 1-1 • Chip-to-Chip Performance (worst-case commercial)

Device and Speed Grade	t _{CKHS} (ns)	t _{TRACE} (ns)	t _{INSU} (ns)	Total (ns)	MHz
A1425A -3	7.5	1.0	1.8	10.3	97
A1460A -3	9.0	1.0	1.3	11.3	88
A1425A -2	7.5	1.0	2.0	10.5	95
A1460A -2	9.0	1.0	1.5	11.5	87
A1425A -1	9.0	1.0	2.3	12.3	81
A1460A -1	10.0	1.0	1.8	12.8	78
A1425A STD	10.0	1.0	2.7	13.7	73
A1460A STD	11.5	1.0	2.0	14.5	69

Note: The -2 and -3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at <http://www.microsemi.com/soc/support/notifications/default.aspx#pdn>.

ACT 3 Timing Model



Note: Values shown for A1425A -1 speed grade device.

Figure 2-10 • Timing Model

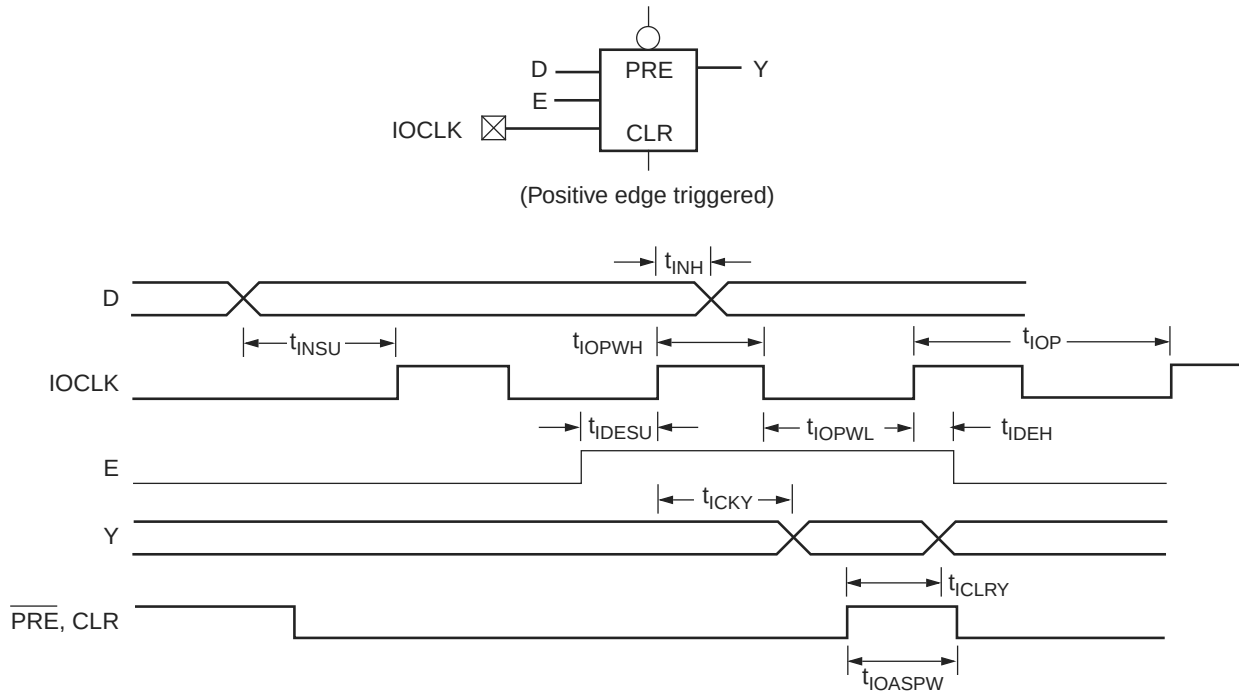


Figure 2-16 • I/O Module: Sequential Input Timing Characteristics

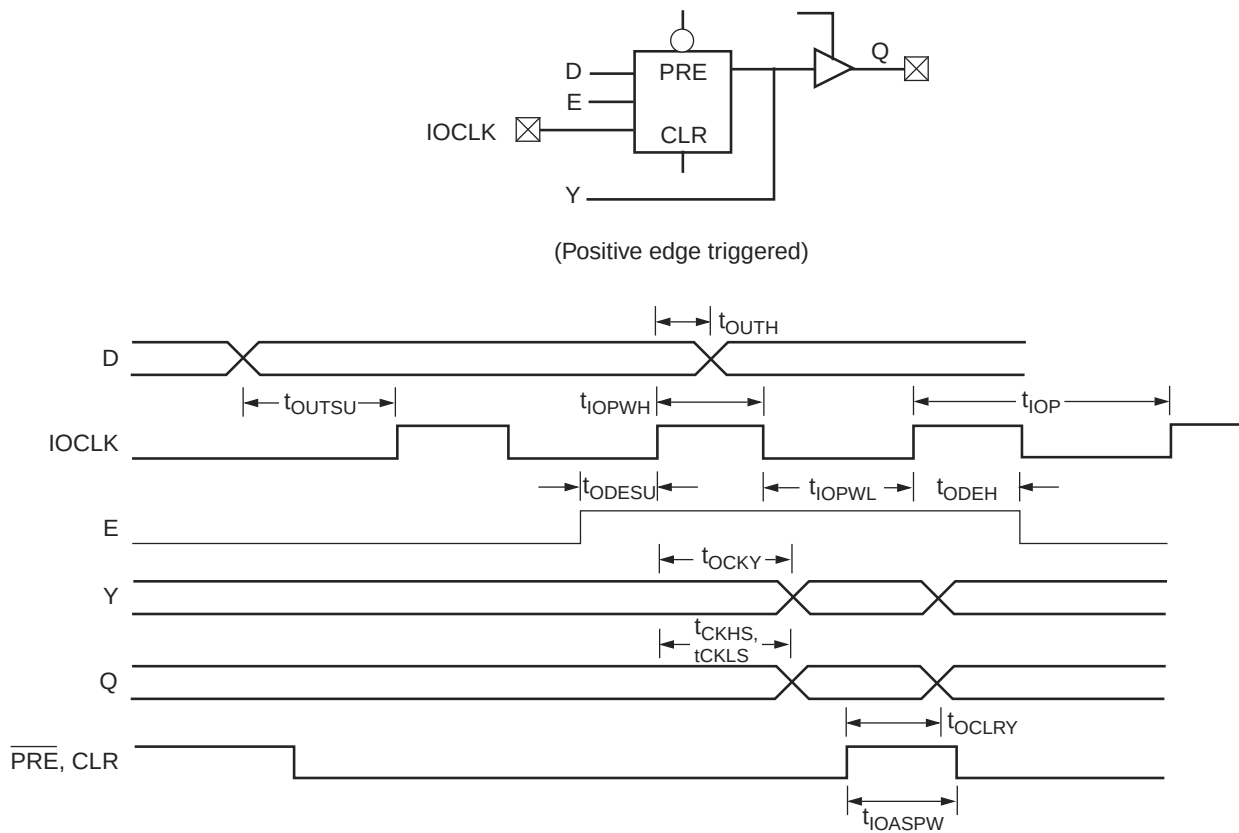


Figure 2-17 • I/O Module: Sequential Output Timing Characteristics

A1415A, A14V15A Timing Characteristics (continued)

Table 2-21 • A1415A, A14V15A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C

Dedicated (hardwired) I/O Clock Network		–3 Speed		–2 Speed		–1 Speed		Std. Speed		3.3 V Speed ¹		Units
Parameter/Description		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{IOCKH}	Input Low to High (pad to I/O module input)		2.0		2.3		2.6		3.0		3.5	ns
t _{IOPWH}	Minimum Pulse Width High	1.9		2.4		3.3		3.8		4.8		ns
t _{IPOWL}	Minimum Pulse Width Low	1.9		2.4		3.3		3.8		4.8		ns
t _{IOSAPW}	Minimum Asynchronous Pulse Width	1.9		2.4		3.3		3.8		4.8		ns
t _{IOCKSW}	Maximum Skew		0.4		0.4		0.4		0.4		0.4	ns
t _{IOP}	Minimum Period	4.0		5.0		6.8		8.0		10.0		ns
f _{IOMAX}	Maximum Frequency		250		200		150		125		100	MHz
Dedicated (hardwired) Array Clock												
t _{HCKH}	Input Low to High (pad to S-module input)		3.0		3.4		3.9		4.5		5.5	ns
t _{HCKL}	Input High to Low (pad to S-module input)		3.0		3.4		3.9		4.5		5.5	ns
t _{HPWH}	Minimum Pulse Width High	1.9		2.4		3.3		3.8		4.8		ns
t _{HPWL}	Minimum Pulse Width Low	1.9		2.4		3.3		3.8		4.8		ns
t _{HCKSW}	Delta High to Low, Low Slew		0.3		0.3		0.3		0.3		0.3	ns
t _{HP}	Minimum Period	4.0		5.0		6.8		8.0		10.0		ns
f _{HMAX}	Maximum Frequency		250		200		150		125		100	MHz
Routed Array Clock Networks												
t _{RCKH}	Input Low to High (FO = 64)		3.7		4.1		4.7		5.5		9.0	ns
t _{RCKL}	Input High to Low (FO = 64)		4.0		4.5		5.1		6.0		9.0	ns
t _{RPWH}	Min. Pulse Width High (FO = 64)	3.3		3.8		4.2		4.9		6.5		ns
t _{RPWL}	Min. Pulse Width Low (FO = 64)	3.3		3.8		4.2		4.9		6.5		ns
t _{RCKSW}	Maximum Skew (FO = 128)		0.7		0.8		0.9		1.0		1.0	ns
t _{RP}	Minimum Period (FO = 64)	6.8		8.0		8.7		10.0		13.4		ns
f _{RMAX}	Maximum Frequency (FO = 64)		150		125		115		100		75	MHz
Clock-to-Clock Skews												
t _{IOHCKSW}	I/O Clock to H-Clock Skew	0.0	1.7	0.0	1.8	0.0	2.0	0.0	2.2	0.0	3.0	ns
t _{IORCKSW}	I/O Clock to R-Clock Skew (FO = 64)	0.0	1.0	0.0	1.0	0.0	1.0	0.0	1.0	0.0	3.0	ns
t _{HRCKSW}	H-Clock to R-Clock Skew (FO = 64) (FO = 50% maximum)	0.0	1.0	0.0	1.0	0.0	1.0	0.0	1.0	0.0	3.0	ns

Notes:

- Delays based on 35 pF loading.
- The –2 and –3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at <http://www.microsemi.com/soc/support/notifications/default.aspx#pdn>.

A1440A, A14V40A Timing Characteristics

Table 2-26 • A1440A, A14V40A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C¹

Logic Module Propagation Delays ²		–3 Speed ³		–2 Speed ³		–1 Speed		Std. Speed		3.3 V Speed ¹		Units
Parameter/Description		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{PD}	Internal Array Module		2.0		2.3		2.6		3.0		3.9	ns
t _{CO}	Sequential Clock to Q		2.0		2.3		2.6		3.0		3.9	ns
t _{CLR}	Asynchronous Clear to Q		2.0		2.3		2.6		3.0		3.9	ns
Predicted Routing Delays⁴												
t _{RD1}	FO = 1 Routing Delay		0.9		1.0		1.1		1.3		1.7	ns
t _{RD2}	FO = 2 Routing Delay		1.2		1.4		1.6		1.8		2.4	ns
t _{RD3}	FO = 3 Routing Delay		1.4		1.6		1.8		2.1		2.8	ns
t _{RD4}	FO = 4 Routing Delay		1.7		1.9		2.2		2.5		3.3	ns
t _{RD8}	FO = 8 Routing Delay		2.8		3.2		3.6		4.2		5.5	ns
Logic Module Sequential Timing												
t _{SUD}	Flip-Flop Data Input Setup	0.5		0.6		0.7		0.8		0.8		ns
t _{HD}	Flip-Flop Data Input Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{SUD}	Latch Data Input Setup	0.5		0.6		0.7		0.8		0.8		ns
t _{HD}	Latch Data Input Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{WASYN}	Asynchronous Pulse Width	1.9		2.4		3.2		3.8		4.8		ns
t _{WCLKA}	Flip-Flop Clock Pulse Width	1.9		2.4		3.2		3.8		4.8		ns
t _A	Flip-Flop Clock Input Period	4.0		5.0		6.8		8.0		10.0		ns
f _{MAX}	Flip-Flop Clock Frequency		250		200		150		125		100	MHz

Notes:

- VCC = 3.0 V for 3.3 V specifications.
- For dual-module macros, use t_{PD} + t_{RD1} + t_{PDn} + t_{CO} + t_{RD1} + t_{PDn} or t_{PD1} + t_{RD1} + t_{SUD}, whichever is appropriate.
- The –2 and –3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at <http://www.microsemi.com/soc/support/notifications/default.aspx#pdn>.
- Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.

A1460A, A14V60A Timing Characteristics

Table 2-30 • A1460A, A14V60A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C¹

Logic Module Propagation Delays ²		–3 Speed ³		–2 Speed ³		–1 Speed		Std. Speed		3.3 V Speed ¹		Units
Parameter/Description		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{PD}	Internal Array Module		2.0		2.3		2.6		3.0		3.9	ns
t _{CO}	Sequential Clock to Q		2.0		2.3		2.6		3.0		3.9	ns
t _{CLR}	Asynchronous Clear to Q		2.0		2.3		2.6		3.0		3.9	ns
Predicted Routing Delays⁴												
t _{RD1}	FO = 1 Routing Delay		0.9		1.0		1.1		1.3		1.7	ns
t _{RD2}	FO = 2 Routing Delay		1.2		1.4		1.6		1.8		2.4	ns
t _{RD3}	FO = 3 Routing Delay		1.4		1.6		1.8		2.1		2.8	ns
t _{RD4}	FO = 4 Routing Delay		1.7		1.9		2.2		2.5		3.3	ns
t _{RD8}	FO = 8 Routing Delay		2.8		3.2		3.6		4.2		5.5	ns
Logic Module Sequential Timing												
t _{SUD}	Flip-Flop Data Input Setup	0.5		0.6		0.7		0.8		0.8		ns
t _{HD}	Flip-Flop Data Input Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{SUD}	Latch Data Input Setup	0.5		0.6		0.7		0.8		0.8		ns
t _{HD}	Latch Data Input Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{WASYN}	Asynchronous Pulse Width	2.4		3.2		3.8		4.8		6.5		ns
t _{WCLKA}	Flip-Flop Clock Pulse Width	2.4		3.2		3.8		4.8		6.5		ns
t _A	Flip-Flop Clock Input Period	5.0		6.8		8.0		10.0		13.4		ns
f _{MAX}	Flip-Flop Clock Frequency		200		150		125		100		75	MHz

Notes:

1. VCC = 3.0 V for 3.3 V specifications.
2. For dual-module macros, use t_{PD} + t_{RD1} + t_{PDn} + t_{CO} + t_{RD1} + t_{PDn} or t_{PD1} + t_{RD1} + t_{SUD}, whichever is appropriate.
3. The –2 and –3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at <http://www.microsemi.com/soc/support/notifications/default.aspx#pdn>.
4. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.

A14100A, A14V100A Timing Characteristics

Table 2-34 • A14100A, A14V100A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C¹

Logic Module Propagation Delays ²		–3 Speed ³		–2 Speed ³		–1 Speed		Std. Speed		3.3 V Speed ¹		Units
Parameter/Description		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{PD}	Internal Array Module		2.0		2.3		2.6		3.0		3.9	ns
t _{CO}	Sequential Clock to Q		2.0		2.3		2.6		3.0		3.9	ns
t _{CLR}	Asynchronous Clear to Q		2.0		2.3		2.6		3.0		3.9	ns
Predicted Routing Delays⁴												
t _{RD1}	FO = 1 Routing Delay		0.9		1.0		1.1		1.3		1.7	ns
t _{RD2}	FO = 2 Routing Delay		1.2		1.4		1.6		1.8		2.4	ns
t _{RD3}	FO = 3 Routing Delay		1.4		1.6		1.8		2.1		2.8	ns
t _{RD4}	FO = 4 Routing Delay		1.7		1.9		2.2		2.5		3.3	ns
t _{RD8}	FO = 8 Routing Delay		2.8		3.2		3.6		4.2		5.5	ns
Logic Module Sequential Timing												
t _{SUD}	Flip-Flop Data Input Setup	0.5		0.6		0.8		0.8		0.8		ns
t _{HD}	Flip-Flop Data Input Hold	0.0		0.0		0.5		0.5		0.5		ns
t _{SUD}	Latch Data Input Setup	0.5		0.6		0.8		0.8		0.8		ns
t _{HD}	Latch Data Input Hold	0.0		0.0		0.5		0.5		0.5		ns
t _{WASYN}	Asynchronous Pulse Width	2.4		3.2		3.8		4.8		6.5		ns
t _{WCLKA}	Flip-Flop Clock Pulse Width	2.4		3.2		3.8		4.8		6.5		ns
t _A	Flip-Flop Clock Input Period	5.0		6.8		8.0		10.0		13.4		ns
f _{MAX}	Flip-Flop Clock Frequency		200		150		125		100		75	MHz

Notes:

1. VCC = 3.0 V for 3.3 V specifications.
2. For dual-module macros, use t_{PD} + t_{RD1} + t_{PDn} + t_{CO} + t_{RD1} + t_{PDn} or t_{PD1} + t_{RD1} + t_{SUD}, whichever is appropriate.
3. The –2 and –3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at <http://www.microsemi.com/soc/support/notifications/default.aspx#pdn>.
4. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.

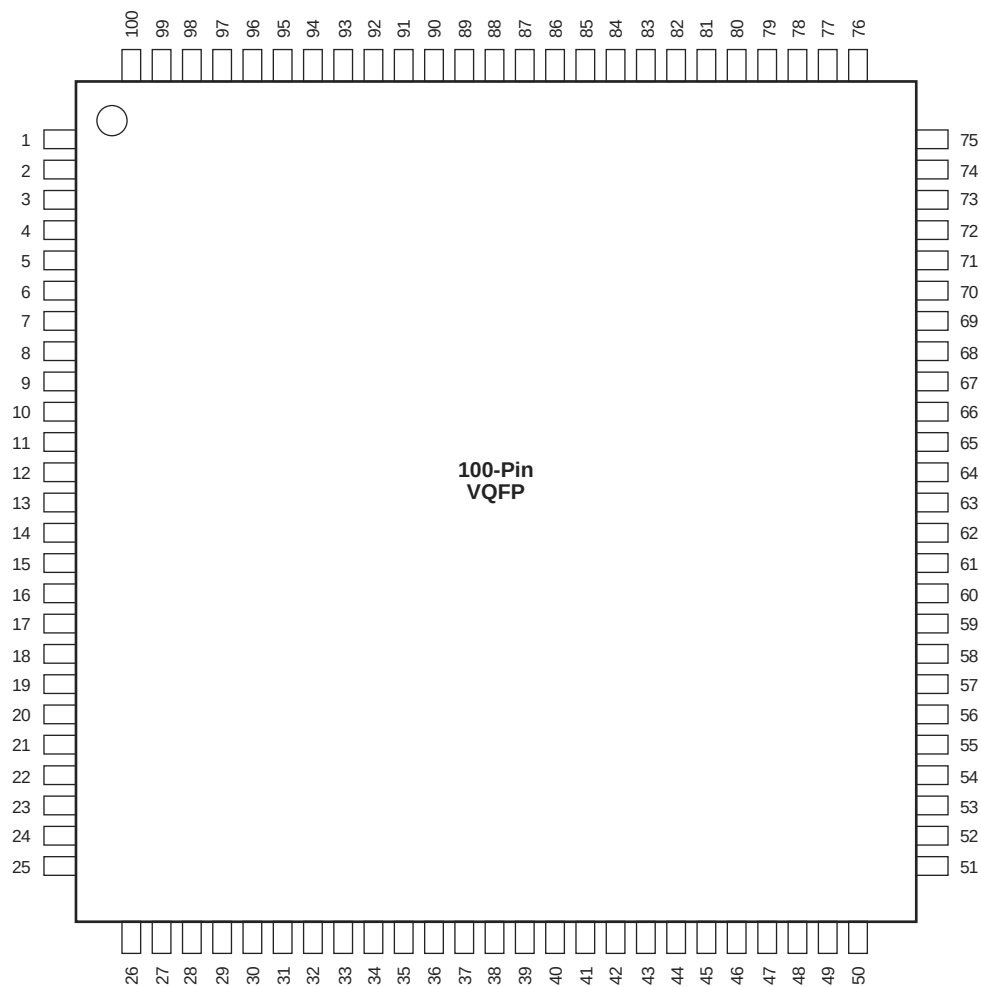
PQ208, RQ208		
Pin Number	A1460, A14V60 Function	A14100, A14V100 Function
1	GND	GND
2	SDI, I/O	SDI, I/O
11	MODE	MODE
12	VCC	VCC
25	VCC	VCC
26	GND	GND
27	VCC	VCC
28	GND	GND
40	VCC	VCC
41	VCC	VCC
52	GND	GND
53	NC	I/O
60	VCC	VCC
65	NC	I/O
76	PRB, I/O	PRB, I/O
77	GND	GND
78	VCC	VCC
79	GND	GND
80	VCC	VCC
82	HCLK, I/O	HCLK, I/O
98	VCC	VCC
102	NC	I/O
103	SDO	SDO
104	IOPCL, I/O	IOPCL, I/O
105	GND	GND
114	VCC	VCC

PQ208, RQ208		
Pin Number	A1460, A14V60 Function	A14100, A14V100 Function
115	VCC	VCC
116	NC	I/O
129	GND	GND
130	VCC	VCC
131	GND	GND
132	VCC	VCC
145	VCC	VCC
146	GND	GND
147	NC	I/O
148	VCC	VCC
156	IOCLK, I/O	IOCLK, I/O
157	GND	GND
158	NC	I/O
164	VCC	VCC
180	CLKA, I/O	CLKA, I/O
181	CLKB, I/O	CLKB, I/O
182	VCC	VCC
183	GND	GND
184	VCC	VCC
185	GND	GND
186	PRA, I/O	PRA, I/O
195	NC	I/O
201	VCC	VCC
205	NC	I/O
208	DCLK, I/O	DCLK, I/O

Notes:

1. All unlisted pin numbers are user I/Os.
2. NC denotes no connection.
3. MODE should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.

VQ100



Note: This is the top view.

Note

For Package Manufacturing and Environmental information, visit the Resource Center at <http://www.microsemi.com/soc/products/solutions/package/docs.aspx>

VQ100			
Pin Number	A1415, A14V15 Function	A1425, A14V25 Function	A1440, A14V40 Function
1	GND	GND	GND
2	SDI, I/O	SDI, I/O	SDI, I/O
7	MODE	MODE	MODE
8	VCC	VCC	VCC
9	GND	GND	GND
20	VCC	VCC	VCC
21	NC	I/O	I/O
34	PRB, I/O	PRB, I/O	PRB, I/O
35	VCC	VCC	VCC
36	GND	GND	GND
37	VCC	VCC	VCC
39	HCLK, I/O	HCLK, I/O	HCLK, I/O
49	SDO	SDO	SDO
50	IOPCL, I/O	IOPCL, I/O	IOPCL, I/O
51	GND	GND	GND
57	VCC	VCC	VCC
58	VCC	VCC	VCC
67	VCC	VCC	VCC
68	GND	GND	GND
69	GND	GND	GND
74	NC	I/O	I/O
75	IOCLK, I/O	IOCLK, I/O	IOCLK, I/O
87	CLKA, I/O	CLKA, I/O	CLKA, I/O
88	CLKB, I/O	CLKB, I/O	CLKB, I/O
89	VCC	VCC	VCC
90	VCC	VCC	VCC
91	GND	GND	GND
92	PRA, I/O	PRA, I/O	PRA, I/O
93	NC	I/O	I/O
100	DCLK, I/O	DCLK, I/O	DCLK, I/O

Notes:

1. All unlisted pin numbers are user I/Os.
2. NC denotes no connection.
3. MODE should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.

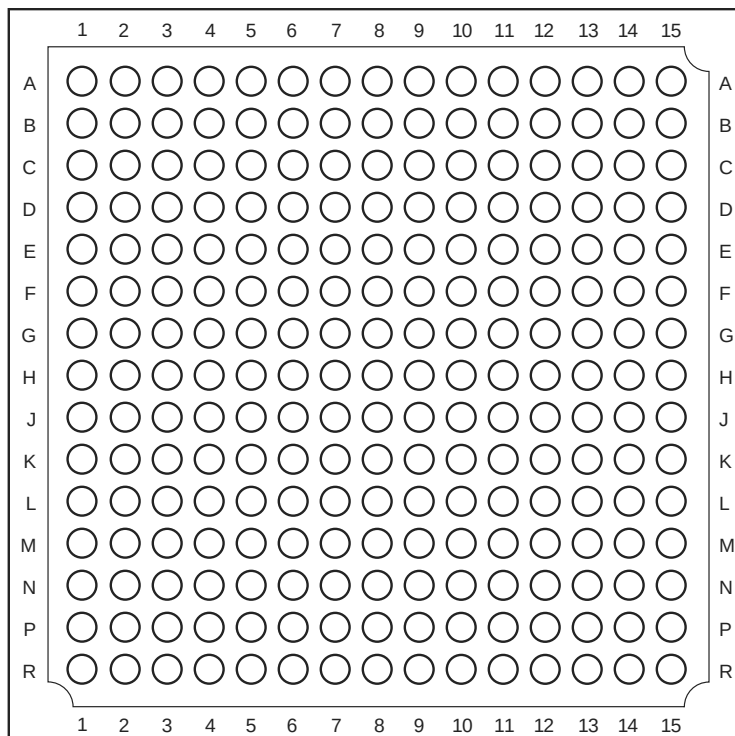
CQ196	
Pin Number	A1460 Function
1	GND
2	SDI, I/O
11	MODE
12	VCC
13	GND
37	GND
38	VCC
39	VCC
51	GND
52	GND
59	VCC
64	GND
77	HCLK, I/O
79	PRB, I/O
86	GND
94	VCC
98	GND
99	SDO
100	IOPCL, I/O

CQ196	
Pin Number	A1460 Function
101	GND
110	VCC
111	VCC
112	GND
137	VCC
138	GND
139	GND
140	VCC
148	IOCLK, I/O
149	GND
155	VCC
162	GND
172	CLKA, I/O
173	CLKB, I/O
174	PRA, I/O
183	GND
189	VCC
193	GND
196	DCLK, I/O

Notes:

1. All unlisted pin numbers are user I/Os.
2. NC denotes no connection.
3. MODE should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.

BG225

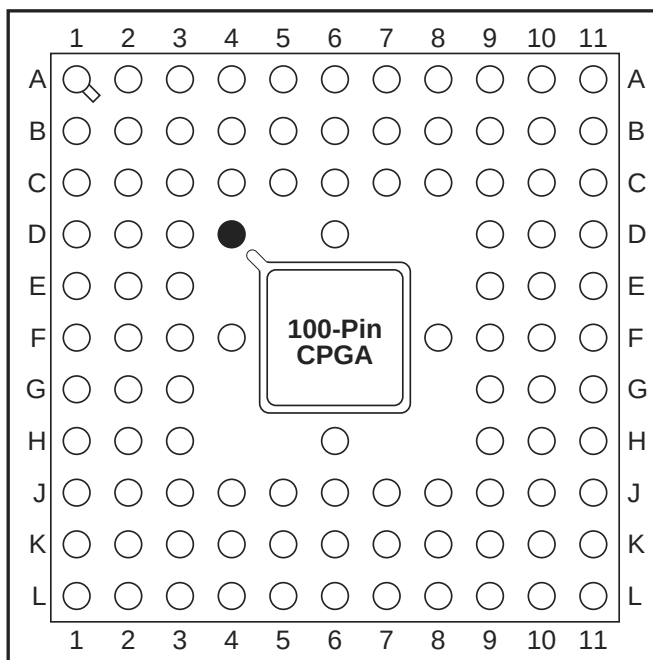


Note: This is the top view.

Note

For Package Manufacturing and Environmental information, visit the Resource Center at <http://www.microsemi.com/soc/products/solutions/package/docs.aspx>

PG100



● Orientation Pin

Note: This is the top view.

Note

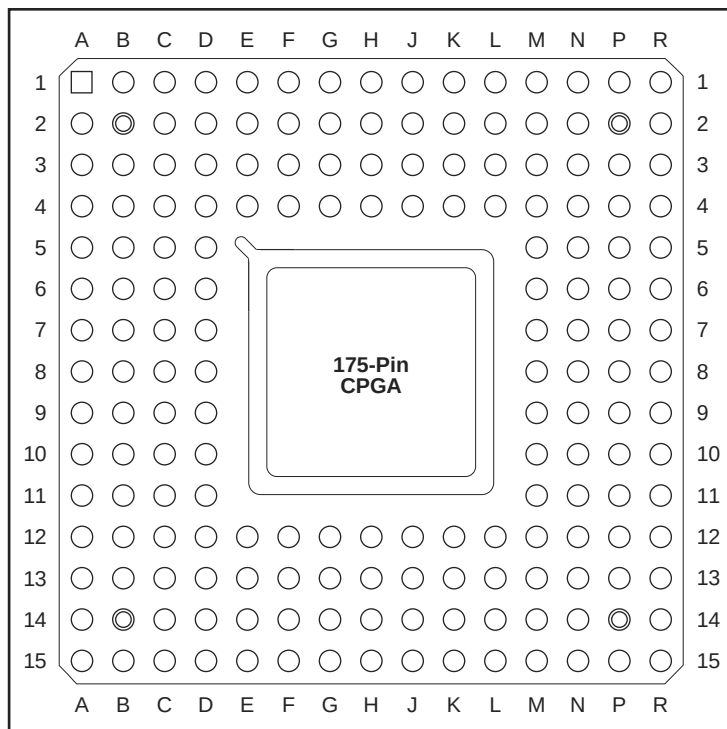
For Package Manufacturing and Environmental information, visit the Resource Center at <http://www.microsemi.com/soc/products/solutions/package/docs.aspx>

PG100	
A1415 Function	Location
CLKA or I/O	C7
CLKB or I/O	D6
DCLK or I/O	C4
GND	C3, C6, C9, E9, F3, F9, J3, J6, J8, J9
HCLK or I/O	H6
IOCLK or I/O	C10
IOPCL or I/O	K9
MODE	C2
PRA or I/O	A6
PRB or I/O	L3
SDI or I/O	B3
SDO	L9
VCC	B6, B10, E11, F2, F10, G2, K2, K6, K10

Notes:

1. All unlisted pin numbers are user I/Os.
2. NC denotes no connection.
3. MODE should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.
4. The PG100 package has been discontinued.

PG175



Note: This is the top view.

Note

For Package Manufacturing and Environmental information, visit the Resource Center at <http://www.microsemi.com/soc/products/solutions/package/docs.aspx>

PG207	
A1460 Function	Location
CLKA or I/O	K1
CLKB or I/O	J3
DCLK or I/O	E4
GND	C14, D4, D5, D9, D14, J4, J14, P3, P4, P7, P9, P14, R15
HCLK or I/O	J15
IOCLK or I/O	P5
IOPCL or I/O	N14
MODE	D7
NC	A1, A2, A16, A17, B1, B17, C1, C2, S1, S3, S17, T1, T2, T16, T17
PRA or I/O	H1
PRB or I/O	K16
SDI or I/O	C3
SDO	P15
VCC	B2, B9, B16, D11, J2, J16, P12, S2, S9, S16, T5

Notes:

1. All unlisted pin numbers are user I/Os.
2. NC denotes no connection.
3. MODE should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.

Datasheet Categories

Categories

In order to provide the latest information to designers, some datasheet parameters are published before data has been fully characterized from silicon devices. The data provided for a given device is designated as either "Product Brief," "Advance," "Preliminary," or "Production." The definitions of these categories are as follows:

Product Brief

The product brief is a summarized version of a datasheet (advance or production) and contains general product information. This document gives an overview of specific device and family information.

Advance

This version contains initial estimated information based on simulation, other products, devices, or speed grades. This information can be used as estimates, but not for production. This label only applies to the DC and Switching Characteristics chapter of the datasheet and will only be used when the data has not been fully characterized.

Preliminary

The datasheet contains information based on simulation and/or initial characterization. The information is believed to be correct, but changes are possible.

Production

This version contains information that is considered to be final.

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